EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1511	356/630,625,628,635,388,237.1. ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2007/05/14 11:58
L2	1	L1 and ((first adj (measured adj data)) and (second adj (measured adj data)) and thickness)	US-PGPUB; USPAT	OR	ON	2007/05/14 12:00
L3	1120	356/630,625,628,635,388237.1.ccls.	US-PGPUB; USPAT	OR	ON	2007/05/14 12:01
L4	732	L3 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2007/05/14 12:01
L5	61	L4 and (galler$3 or librar$3)	US-PGPUB; USPAT	OR	ON	2007/05/14 12:01
L6	56	L5 and (interpret$3 or compar$3)	US-PGPUB; USPAT	OR	ON	2007/05/14 12:01
L7	44	L6 and layer$1 and thickness	US-PGPUB; USPAT	OR	ON	2007/05/14 12:03
S1	5	punnoose.xa. and finarov.in.	US-PGPUB; USPAT	OR	ON	2005/10/16 19:02
S2	5	S1 and thickness	US-PGPUB; USPAT	OR	ON	2005/10/16 17:38
S3	5	S2 and (control$4 with process$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 16:59
S4	5	S3 and layer$1	US-PGPUB; USPAT	OR	ON	2005/10/16 18:49
S5	0	S4 and quality.clm.	US-PGPUB; USPAT	OR	ON	2005/10/16 17:01
S6	3	S4 and quality	US-PGPUB; USPAT	OR	ON	2005/10/16 17:54
S7	1428	kla adj tencor	US-PGPUB; USPAT	OR	ON	2005/10/16 17:12
S8	22	S7 and 356/630.ccls.	US-PGPUB; USPAT	OR	ON	2005/10/16 18:46
S9	334	356/630.ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S10	34	S9 and (galler$3 or librar$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S11	22	S10 and (second with measur$5)	US-PGPUB; USPAT	OR	ON	2005/10/16 17:25
S12	20	S11 and (interpret$3 or compar$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S13	16	S11 and (interpret$3 or compar$3). clm.	US-PGPUB; USPAT	OR	ON	2005/10/16 17:26

S14	0	(interpret$3 or compar$3) adj ((first with measured) adj3 "with")	US-PGPUB; USPAT	OR	ON	2005/10/16 17:36
S15	9	(interpret$3 or compar$3) adj (first with measured)	US-PGPUB; USPAT	OR	ON	2005/10/16 17:37
S16	4	S15 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 17:36
S17	17	"356"/$.ccls. and (layer and thickness and (galler$3 or librar$3) and (interpret$3 or compar$3)). clm.	US-PGPUB; USPAT	OR	ON	2005/10/16 17:39
S18	11	S17 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 17:51
S19	4	("5751427" | "5963329" | "6268916" | "6657736").PN. OR ("6900892").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/16 17:51
S20	4	S19 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 17:51
S21	936	356/630,625,628,635,388237.1.ccls.	US-PGPUB; USPAT	OR	ON	2005/10/17 10:33
S22	715	S21 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 10:33
S23	59	S22 and (galler$3 or librar$3)	US-PGPUB; USPAT	OR	ON	2005/10/17 10:34
S24	54	S23 and (interpret$3 or compar$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S25	42	S24 and layer$1 and thickness	US-PGPUB; USPAT	OR	ON	2007/05/14 12:01
S26	4	("5751427" | "5963329" | "6268916" | "6657736").PN. OR ("6900892").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/16 18:54
S27	4	S26 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 18:54
S28	334	356/630.ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 18:57
S29	6	finarov.in. and (galler$3 or librar$3) and layer$1 and thickness and process	US-PGPUB; USPAT	OR	ON	2005/10/16 19:03
S30	5	S29 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 19:04
S31	4	("5604344" | "6113733").PN. OR ("6643017").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/17 09:59
S32	3	S31 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 10:04

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S33	2	(((analyzing adj second) with (based with first)) and (semiconductor or wafer)) and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 10:06
S34	1907	356/630,625,628,635,388,237.1. ccls.	US-PGPUB; USPAT	OR	ON	2005/10/17 10:33
S35	1465	S34 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 11:34
S36	73	S35 and (galler$3 or librar$3)	US-PGPUB; USPAT	OR	ON	2005/10/17 10:34
S37	52	S36 and layer$1 and thickness	US-PGPUB; USPAT	OR	ON	2005/10/17 10:53
S38	29	S36 and etching and (measur$4 with thickness)	US-PGPUB; USPAT	OR	ON	2005/10/17 11:19
S39	49	((first adj measur$4) same (second adj measur$4) same compar$3) and (measur$4 with thickness)	US-PGPUB; USPAT	OR	ON	2005/10/17 11:20
S40	30	S39 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 11:28
S41	67	(surface adj profile$3) and (measur$4 with thickness) and ((compar$3 or analyze) with first with second) and (wafer or semiconductor)	US-PGPUB; USPAT	OR	ON	2005/10/17 12:12
S42	46	S41 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2006/08/07 10:36
S43	3	(("5,609,718") or ("5,655,951") or ("5,801,066")).PN.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:40
S44	388	(measur$4 with thickness) and ((compar$3 or analyze) with first with second).clm. and (wafer or semiconductor)	US-PGPUB; USPAT	OR	ON	2005/10/17 14:34
S45	260	S44 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 12:16
S46	26	("5081796" | "5413941" | "5433651" | "5605760" | "5640242" | "5672091" | "5791969" | "5838447" | "5872633" | "5893796" | "5899792" | "5949927" | "5964643" | "6159073").PN. OR ("6296548").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/17 13:05
S47	24	S46 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 13:05
S48	0	(measur$4 with thickness) and ((compar$3 or analyze) with first with second).clm. and (wafer or semiconductor)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/17 14:38

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S49	2	(("6045433") or ("5393624")).PN.	US-PGPUB; USPAT	OR	OFF	2005/10/17 14:38
S50	75	("3707760" | "4121936" | "4285433" | "4500615" | "4738910" | "4778326" | "4841156" | "4851311" | "4977330" | "5220405").PN. OR ("5393624"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/17 14:39
S51	0	(2002/0037462).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/08/07 10:36
S52	1	("20020037462").PN.	US-PGPUB; USPAT	OR	OFF	2006/08/07 10:43
S53	1	("20020037462").PN.	US-PGPUB; USPAT	OR	OFF	2006/08/07 10:44
S54	1	"20020037462".pn. and (measured adj data)	US-PGPUB; USPAT	OR	ON	2006/08/07 10:45
S55	1	"20020037462".pn. and (second adj (measured adj data)) and thickness	US-PGPUB; USPAT	OR	ON	2006/08/07 10:55
S56	1	S55 and (first adj (measured adj data))	US-PGPUB; USPAT	OR	ON	2006/08/07 11:42
S57	1	S56 and quality	US-PGPUB; USPAT	OR	ON	2006/08/07 11:05
S58	0	S56 and (surfacee and profile)	US-PGPUB; USPAT	OR	ON	2006/08/07 11:05
S59	0	S56 and (surface and profile)	US-PGPUB; USPAT	OR	ON	2006/08/07 11:06
S60	0	S56 and (profile)	US-PGPUB; USPAT	OR	ON	2006/08/07 11:06
S61	1	S56 and (surface)	US-PGPUB; USPAT	OR	ON	2006/08/07 11:24
S62	1	S61 and (remov$3)	US-PGPUB; USPAT	OR	ON	2006/08/07 11:40
S63	1497	356/630,625,628,635,388,237.1. ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2006/08/07 11:44
S64	1	S63 and ((first adj (measured adj data)) and (second adj (measured adj data)) and thickness)	US-PGPUB; USPAT	OR	ON	2007/05/14 11:58
S65	1211	430/30.ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2006/08/07 11:44
S66	2	S65 and ((first adj (measured adj data)) and (second adj (measured adj data)) and thickness)	US-PGPUB; USPAT	OR	ON	2006/08/07 11:45
S67	1	((first adj (measured adj data)) and (second adj (measured adj data)) and thickness)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/07 11:45